

| L Number | Hits | Search Text | DB | Time stamp |
|----------|------|--|-------------------|------------------|
| 1 | 1495 | (c23c016\$.ipc. h011021\$.ipc. c23f01\$.ipc.) and (control\$4 same (transfer\$4 transport\$3) same (inspect\$3 observ\$5 test\$3 measur\$3 detect\$3)) | EPO; JPO; DERWENT | 2004/01/20 16:39 |
| 2 | 734 | (c23c016\$.ipc. h011021\$.ipc. c23f01\$.ipc.) and (control\$4 with (transfer\$4 transport\$3) with (inspect\$3 observ\$5 test\$3 measur\$3 detect\$3)) | EPO; JPO; DERWENT | 2004/01/20 16:39 |
| 3 | 206 | (c23c016\$.ipc. h011021\$.ipc. c23f01\$.ipc.) and (control\$4 same (transfer\$4 transport\$3) same (inspect\$3 observ\$5 test\$3 measur\$3 detect\$3) same ((set group plurality part portion fraction) with (wafer substrate))) | EPO; JPO; DERWENT | 2004/01/20 17:07 |
| 4 | 0 | 156/345.124 | USPAT; US-PGPUB | 2004/01/20 17:08 |
| 6 | 90 | (156/345.24.ccls. 156/345.15.ccls.) and (control\$4 same (transfer\$4 transport\$3)) | USPAT; US-PGPUB | 2004/01/20 17:09 |
| 5 | 9 | (156/345.24.ccls. 156/345.15.ccls.) and (control\$4 same (transfer\$4 transport\$3) same (inspect\$3 observ\$5 test\$3 measur\$3 detect\$3) same ((set group plurality part portion fraction) with (wafer substrate))) | USPAT; US-PGPUB | 2004/01/20 17:10 |
| 7 | 33 | (156/345.24.ccls. 156/345.15.ccls.) and (control\$4 same (transfer\$4 transport\$3) same (inspect\$3 observ\$5 test\$3 measur\$3 detect\$3)) | USPAT; US-PGPUB | 2004/01/20 17:10 |
| - | 79 | (US-5963753-\$ or US-5417537-\$ or US-5405230-\$ or US-6503365-\$ or US-6473151-\$ or US-6439822-\$ or US-6377329-\$ or US-6391114-\$ or US-5286296-\$ or US-6328768-\$ or US-6270619-\$ or US-6251191-\$ or US-6235171-\$ or US-6183564-\$ or US-6168667-\$ or US-4981408-\$ or US-4927484-\$ or US-6467491-\$ or US-6051101-\$ or US-5788868-\$ or US-6511315-\$ or US-6464789-\$ or US-6299363-\$ or US-6253118-\$ or US-6224274-\$ or US-6099643-\$).did. or (US-6024502-\$ or US-5820679-\$ or US-5769952-\$ or US-5766360-\$ or US-5695564-\$ or US-5937223-\$ or US-5733024-\$ or US-5639301-\$ or US-5626675-\$ or US-5571325-\$ or US-5565034-\$ or US-5544421-\$ or US-5430271-\$ or US-5061144-\$ or US-4787800-\$ or US-6402400-\$ or US-5974682-\$ or US-5942013-\$ or US-5826129-\$ or US-5725664-\$ or US-6402401-\$ or US-6074154-\$ or US-5803932-\$ or US-4985722-\$ or US-6313903-\$ or US-6379056-\$ or US-6290405-\$).did. or (US-6240874-\$ or US-6544338-\$ or US-6515731-\$ or US-6341903-\$ or US-6322119-\$ or US-6293713-\$ or US-6267516-\$ or US-6264705-\$ or US-6264381-\$ or US-6245156-\$ or US-6215545-\$ or US-6002108-\$ or US-5915396-\$ or US-5766824-\$ or US-5668733-\$ or US-5664254-\$ or US-5651823-\$ or US-5442416-\$ or US-5202716-\$).did. or (US-20030019578-\$ or US-20020189758-\$ or US-20020137346-\$ or US-20010008174-\$ or US-20020197878-\$ or US-20020092368-\$ or US-20020009658-\$).did. or (JP-2002184706-\$).did. or (EP-1184895-\$).did. | USPAT; US-PGPUB | 2003/06/05 12:05 |

| | | | | |
|---|------|--|----------------------|------------------|
| - | 14 | ((US-5963753-\$ or US-5417537-\$ or US-5405230-\$ or US-6503365-\$ or US-6473151-\$ or US-6439822-\$ or US-6377329-\$ or US-6391114-\$ or US-5286296-\$ or US-6328768-\$ or US-6270619-\$ or US-6251191-\$ or US-6235171-\$ or US-6183564-\$ or US-6168667-\$ or US-4981408-\$ or US-4927484-\$ or US-6467491-\$ or US-6051101-\$ or US-5788868-\$ or US-6511315-\$ or US-6464789-\$ or US-6299363-\$ or US-6253118-\$ or US-6224274-\$ or US-6099643-\$).did. or (US-6024502-\$ or US-5820679-\$ or US-5769952-\$ or US-5766360-\$ or US-5695564-\$ or US-5937223-\$ or US-5733024-\$ or US-5639301-\$ or US-5626675-\$ or US-5571325-\$ or US-5565034-\$ or US-5544421-\$ or US-5430271-\$ or US-5061144-\$ or US-4787800-\$ or US-6402400-\$ or US-5974682-\$ or US-5942013-\$ or US-5826129-\$ or US-5725664-\$ or US-6402401-\$ or US-6074154-\$ or US-5803932-\$ or US-4985722-\$ or US-6313903-\$ or US-6379056-\$ or US-6290405-\$).did. or (US-6240874-\$ or US-6544338-\$ or US-6515731-\$ or US-6341903-\$ or US-6322119-\$ or US-6293713-\$ or US-6267516-\$ or US-6264705-\$ or US-6264381-\$ or US-6245156-\$ or US-6215545-\$ or US-6002108-\$ or US-5915396-\$ or US-5766824-\$ or US-5668733-\$ or US-5664254-\$ or US-5651823-\$ or US-5442416-\$ or US-5202716-\$).did. or (US-20030019578-\$ or US-20020189758-\$ or US-20020137346-\$ or US-20010008174-\$ or US-20020197878-\$ or US-20020092368-\$ or US-20020009658-\$).did. or (JP-2002184706-\$).did. or (EP-1184895-\$).did.) and (inspect\$3 ("5256204").PN. | USPAT; US-PGPUB | 2003/06/05 12:05 |
| - | 1 | | USPAT; US-PGPUB | 2003/06/05 16:44 |
| - | 1836 | ((118/719) or (414/939) or (156/345.31) or (156/345.32)).CCLS. | USPAT; US-PGPUB | 2004/01/14 13:45 |
| - | 13 | ((118/719) or (414/939) or (156/345.31) or (156/345.32)).CCLS.) and (inspect\$3 with sampl\$3) | USPAT; US-PGPUB | 2004/01/14 13:45 |
| - | 3 | c23c016\$.ipc. and (inspect\$3 with sampl\$3) | EPO; JPO; DERWENT | 2004/01/14 13:45 |
| - | 555 | (427/\$.ccls. 438/\$.ccls. 216/\$.ccls.) and (inspect\$3 with sampl\$3) | USPAT; US-PGPUB | 2004/01/14 13:46 |
| - | 122 | (427/\$.ccls. 438/\$.ccls. 216/\$.ccls.) and ((inspect\$3 with sampl\$3) with (wafer substrate)) | USPAT; US-PGPUB | 2004/01/14 13:47 |
| - | 46 | (427/\$.ccls. 438/\$.ccls. 216/\$.ccls.) and ((inspect\$3 with sampl\$3) with (control\$3 program\$3 procedur\$3 instruct\$3 computer\$4)) | USPAT; US-PGPUB | 2004/01/14 13:49 |
| - | 46 | (427/\$.ccls. 438/\$.ccls. 216/\$.ccls.) and ((inspect\$3 with sampl\$3) with (control\$3 program\$3 procedur\$3 instruct\$4 computer\$4)) | USPAT; US-PGPUB | 2004/01/14 14:02 |
| - | 2 | ((118/719) or (414/939) or (156/345.31) or (156/345.32)).CCLS.) and ((inspect\$3 with sampl\$3) with (control\$3 program\$3 procedur\$3 instruct\$4 computer\$4)) | USPAT; US-PGPUB | 2004/01/14 14:03 |
| - | 107 | ((inspect\$3 with sampl\$3) with (control\$3 program\$3 procedur\$3 instruct\$4 computer\$4) with (wafer substrate semiconductor)) | USPAT; US-PGPUB | 2004/01/14 15:36 |

| | | | | |
|---|-----|--|----------------------|------------------|
| - | 6 | 6208751.URPN. | USPAT | 2004/01/14 15:13 |
| - | 4 | ("4618938" "4764969" "5614837" "5699447").PN. | USPAT | 2004/01/14 15:15 |
| - | 13 | (inspect\$3 measur\$3 observ\$3 detect\$3) with sampl\$3 with (control\$3 program\$3 procedur\$3 instruct\$4 computer\$4) with (wafer substrate semiconductor) with (one single each) with (set group) | USPAT; US-PGPUB | 2004/01/14 15:53 |
| - | 4 | (inspect\$3 measur\$3 observ\$3 detect\$3) with sampl\$3 with (control\$3 program\$3 procedur\$3 instruct\$4 computer\$4) with (wafer substrate semiconductor) with (one single each) with (set group) | EPO; JPO; DERWENT | 2004/01/14 15:54 |
| - | 5 | (inspect\$3 measur\$3 observ\$3 detect\$3) with sampl\$3 with (control\$3 program\$3 procedur\$3 instruct\$4 computer\$4) with (wafer substrate semiconductor) with (one single each) with (set group pluralit\$3) | EPO; JPO; DERWENT | 2004/01/14 17:04 |
| - | 1 | ("5766360").PN. | USPAT; US-PGPUB | 2004/01/14 17:05 |
| - | 1 | ("6593045").PN. | USPAT; US-PGPUB | 2004/01/14 17:08 |
| - | 3 | ("5899690" "5915910" "6051349").PN. | USPAT | 2004/01/14 17:05 |
| - | 146 | inspect\$3 with coat\$3 with develop\$3 | USPAT; US-PGPUB | 2004/01/14 17:38 |
| - | 47 | SHIGA-MASAYOSHI.in. HASHINOKI-KENJI.in. OHTANI-MASAMI.in. NISHIMURA-JOICHI.in. | USPAT; US-PGPUB | 2004/01/20 16:29 |